

Search Notes				Application/Control No.		Applicant(s)/Patent under Reexamination	
				10/806,170		ONISHI, KAZUYOSHI	
				Examiner		Art Unit	
				Tran N. Nguyen		2834	
SEARCHED				SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
Class	Subclass	Date	Examiner			DATE	EXMR
310	215	4/15/05	TMN	(29/596, 598, 837 868, 506, 734 512, 507, 736, 513)		4/15/05	
				and (slit same (insulat\$ line))			
INTERFERENCE SEARCHED							
Class	Subclass	Date	Examiner				